

Notice of References Cited	Application/Control No. 10/029,846		Applicant(s)/Patent Under Reexamination SHIH ET AL.	
	Examiner Jacob P. Rohwer		Art Unit 2625	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,144,772	11-2000	Garland et al.	382/239
*	B	US-2002/0012126	01-2002	Nakamura, Hiroaki	358/1.9
	C	US-			
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	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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